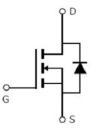


Main Product Characteristics:

V _{DSS}	200V
R _{DS} (on)	0.13ohm(typ.)
I _D	18A ①







TO220

Marking and pin
Assignment

Schematic diagram

Features and Benefits:

- Advanced Process Technology
- Special designed for PWM, load switching and general purpose applications
- Ultra low on-resistance with low gate charge
- Fast switching and reverse body recovery
- 175°C operating temperature



Description:

These N-Channel enhancement mode power field effect transistors are produced using silikron proprietary MOSFET technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency switch mode power supplies.

Absolute max Rating:

Symbol	Parameter	Max.	Units
I _D @ TC = 25°C	Continuous Drain Current, V _{GS} @ 10V	18 ①	
I _D @ TC = 100°C	Continuous Drain Current, V _{GS} @ 10V	13 ①	Α
I _{DM}	Pulsed Drain Current ②	72	
D @TC 25°C	Power Dissipation ③	150	W
P _D @TC = 25°C	Linear Derating Factor	1.0	W/°C
V _{DS}	Drain-Source Voltage	200	V
V _{GS}	Gate-to-Source Voltage		V
E _{AS}	Single Pulse Avalanche Energy @ L=4.2mH	412	mJ
I _{AS}	Avalanche Current @ L=4.2mH	14	Α
T _J T _{STG}	Operating Junction and Storage Temperature Range	-55 to +175	°C



Thermal Resistance

Symbol	Characterizes	Тур.	Max.	Units
$R_{ heta JC}$	Junction-to-case ③	_	1.0	°C/W
В	Junction-to-ambient (t $ \leqslant 10 \mathrm{s}) \oplus$	_	62	°C/W
$R_{\theta JA}$	Junction-to-Ambient (PCB mounted, steady-state) ④	_	40	°C/W

Electrical Characterizes $@T_A=25^{\circ}C$ unless otherwise specified

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
$V_{(BR)DSS}$	Drain-to-Source breakdown voltage	200	_	_	V	$V_{GS} = 0V, I_D = 250\mu A$
D	0		0.13	0.15	0	V _{GS} =10V,I _D =11A
$R_{DS(on)}$	Static Drain-to-Source on-resistance	_	0.27	_	Ω	T _J = 125°C
V	Cata threehold voltage	2	_	4	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
$V_{GS(th)}$	Gate threshold voltage	_	2.26	_	V	T _J = 125°C
	Drain to Course leekage gurrent	_	_	1		V _{DS} =200V,V _{GS} = 0V
I _{DSS}	Drain-to-Source leakage current	_	_	50	μA	T _J = 125°C
	Cata ta Causaa famuand laakana	_	_	100	A	V _{GS} =20V
I _{GSS}	Gate-to-Source forward leakage	_	_	-100	nA	V _{GS} = -20V
Q_g	Total gate charge	_	22.0	_	nC	I _D = 18A,
Q _{gs}	Gate-to-Source charge	_	6.6	_		V _{DS} =160V,
Q _{gd}	Gate-to-Drain("Miller") charge	_	7.2	_		V _{GS} = 10V
t _{d(on)}	Turn-on delay time	_	11.0	_		V _{GS} =10V, V _{DD} =100V,
t _r	Rise time	_	25.5	_	nS	$R_L=9.2\Omega$,
t _{d(off)}	Turn-Off delay time	_	21.9	_		$R_{GEN}=2.55\Omega$
t _f	Fall time	_	5.2	_		I _D =11A
C _{iss}	Input capacitance	_	1038	_		$V_{GS} = 0V$
Coss	Output capacitance	_	232	_	pF	V _{DS} = 25V
C _{rss}	Reverse transfer capacitance	_	51	_		f = 1MHz

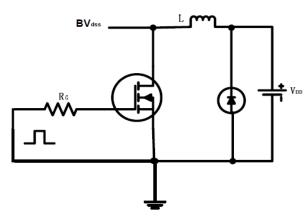
Source-Drain Ratings and Characteristics

Symbol	Parameter	Min.	Тур.	Max.	Units	Conditions
1	Continuous Source Current			10 ①	А	MOSFET symbol
Is	(Body Diode)	_		18 ①	A	showing the
I _{SM}	Pulsed Source Current			72	А	integral reverse
	(Body Diode)	_	_			p-n junction diode.
V _{SD}	Diode Forward Voltage	_	0.89	1.3	V	I _S =11A, V _{GS} =0V, T _J = 25°C
t _{rr}	Reverse Recovery Time	_	136	_	nS	$T_J = 25^{\circ}C, I_F = 11A, di/dt =$
Q _{rr}	Reverse Recovery Charge	_	900	_	nC	100A/μs

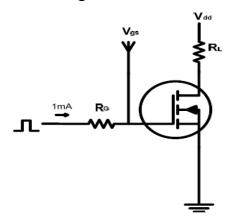


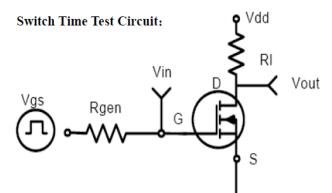
Test circuits and Waveforms

EAS test circuits:

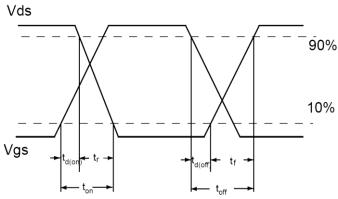


Gate charge test circuit:





Switch Waveforms:

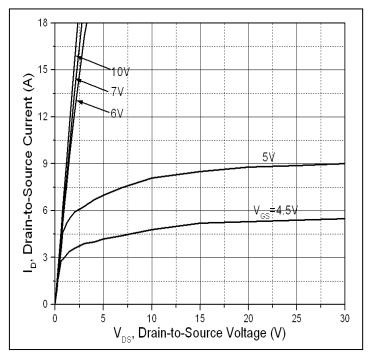


Notes:

- ①Calculated continuous current based on maximum allowable junction temperature. Package limitation current is 75A.
- ②Repetitive rating; pulse width limited by max. junction temperature.
- ③The power dissipation PD is based on max. junction temperature, using junction-to-case thermal resistance.
- 4The value of $R_{\texttt{9JA}}$ is measured with the device mounted on 1 in 2 FR-4 board with 2oz. Copper, in a still air environment with TA =25°C
- ⑤These curves are based on the junction-to-case thermal impedence which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of $T_{J(MAX)}=175$ °C.



Typical electrical and thermal characteristics



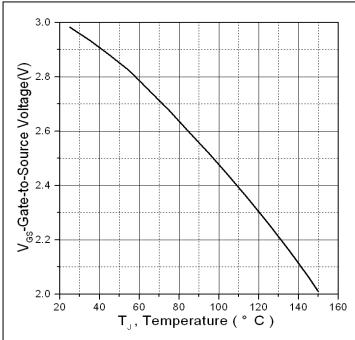


Figure 1: Typical Output Characteristics

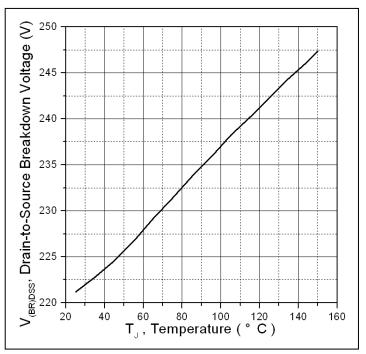


Figure 3. Drain-to-Source Breakdown Voltage vs.
Temperature

Figure 2. Gate to source cut-off voltage

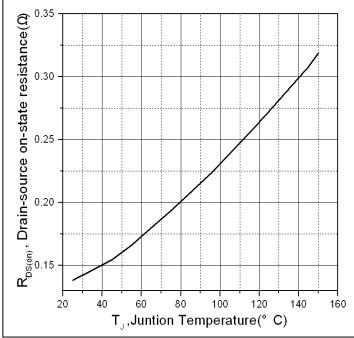
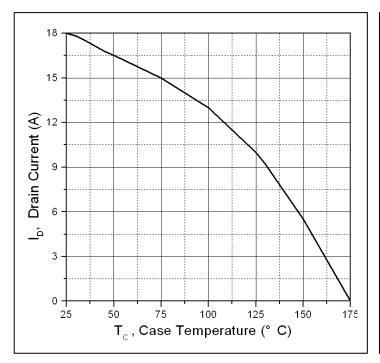


Figure 4: Normalized On-Resistance Vs. Case Temperature



Typical electrical and thermal characteristics



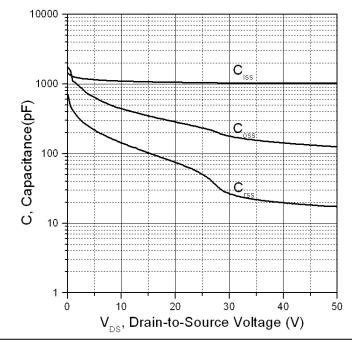


Figure 5. Maximum Drain Current Vs. Case Temperature

Figure 6.Typical Capacitance Vs. Drain-to-Source Voltage

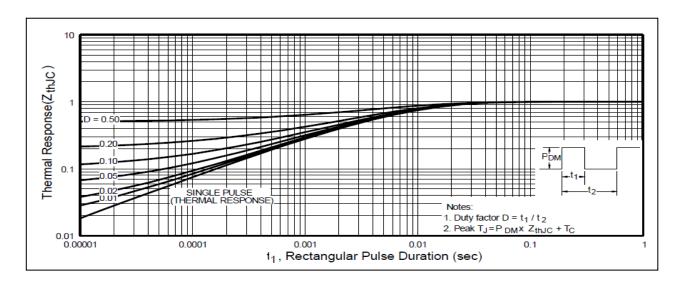
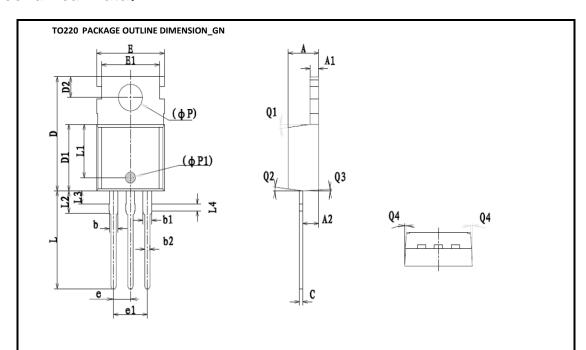


Figure 7. Maximum Effective Transient Thermal Impedance, Junction-to-Case



Mechanical Data:



Comple ed	Dime	nsion In Millin	neters	Dimension In Inches			
Symbol	Min	Nom	Max	Min	Nom	Max	
А	4.400	4.550	4.700	0.173	0.179	0.185	
A1	1.270	1.300	1.330	0.050	0.051	0.052	
A2	2.240	2.340	2.440	0.088	0.092	0.096	
b	-	1.270	=	-	0.050	-	
b1	1.270	1.370	1.470	0.050	0.054	0.058	
b2	0.750	0.800	0.850	0.030	0.031	0.033	
С	0.480	0.500	0.520	0.019	0.020	0.021	
D	15.100	15.400	15.700	0.594	0.606	0.618	
D1	8.800	8.900	9.000	0.346	0.350	0.354	
D2	2.730	2.800	2.870	0.107	0.110	0.113	
Е	9.900	10.000	10.100	0.390	0.394	0.398	
E1	-	8.700	-	-	0.343	-	
ΦР	3.570	3.600	3.630	0.141	0.142	0.143	
ФР1	1.400	1.500	1.600	0.055	0.059	0.063	
е		2.54BSC		0.1BSC			
e1		5.08BSC		0.2BSC			
L	13.150	13.360	13.570	0.518	0.526	0.534	
L1		7.35REF 0.29REF					
L2	2.900	3.000	3.100	0.114	0.118	0.122	
L3	1.650	1.750	1.850	0.065	0.069	0.073	
L4	0.900	1.000	1.100	0.035	0.039	0.043	
Q1	5°	7 ⁰	90	5 ⁰	7 ⁰	90	
Q2	5 ⁰	7 ⁰	90	5 ⁰	7 ⁰	90	
Q3	5 ⁰	7 ⁰	90	5 ⁰	7 ⁰	90	
Q4	1 ⁰	3 ⁰	5 ⁰	1 ⁰	3 ⁰	5 ⁰	





Ordering and Marking Information

Device Marking: SSPL2015

Package (Available) TO220 Operating Temperature Range

C:-55 to175 °C

Devices per Unit

Package	Units/	Tubes/Inner	Units/Inner	Inner	Units/Carton
Type	Tube	Box	Box	Boxes/Carton	Box
				Box	

Reliability Test Program

Test Item	Conditions	Duration	Sample Size
High	T _j =125℃ to 175℃ @	168 hours	3 lots x 77 devices
Temperature	80% of Max	500 hours	
Reverse	V _{DSS} /V _{CES} /VR	1000 hours	
Bias(HTRB)			
High	T _j =125℃ or 175℃ @	168 hours	3 lots x 77 devices
Temperature	100% of Max V _{GSS}	500 hours	
Gate		1000 hours	
Bias(HTGB)			



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